

**Deassy I. Novita**

Lives in Hillsboro Oregon

Education

B.S. in Electrical Engineering,
University of Cincinnati, Cincinnati,
Ohio (2003)

Ph.D. in Electrical Engineering,
University of Cincinnati, Ohio
(2009)

Previous Employment:

2009 - 2013: Printed Circuit Board Technology Development Engineer, Intel Corp., Hillsboro Oregon.

2007: Higher Education Research Experience Intern, program duration: 1 quarter, The United States Oak Ridge National Lab., Oak Ridge, Tennessee.

2006: Electrical Engineering Teaching Assistant, University of Cincinnati College of Eng., Cincinnati, Ohio.

2002: Electrical Engineer Control Systems Co-Op, General Electrical Aircraft Engine, Cincinnati, Ohio.

Current Job Description:

Semiconductor Packaging Electrical Design and Analysis, Intel Corp., Hillsboro, Oregon

Publications:

1. D. I. Novita, G. Brist, G. Long, "Impact of lead-free Assembly on Laminate Electrical Performance for High Layer Count High Reliability PCBs", Surface Mount Technology Association International Proceeding (2013).
2. T. Embree, D.I. Novita, G. Long, S. Parupalli, "Printed circuit board pad crater test methods and sample design", J. of Amer. Soc. Of Mech. Eng. (2012).
3. M. Micoulaut, M. Malki, D. I. Novita, and P. Boolchand, "Fast-ion conduction and flexibility and rigidity of solid electrolyte glasses", Phys. Review B, 80, 184205 (2009). (12 citations).
4. K. Rompicharla, D. I. Novita, P. Chen, P. Boolchand et al., "Abrupt Boundaries of Intermediate Phases and Space Filling in Oxide Glasses", J. Phys.: Condens. Matter 20, 202101 (2008). (17 citations).
5. D. I. Novita and P. Boolchand, "Synthesis and Structural Characterization of Dry AgPO₃ Glass By Raman Scattering, Infrared Reflectance, and Modulated Differential Scanning Calorimetry", Physical Review B 76, 184205 (2007). (12 citations).
6. D. I. Novita, P. Boolchand, M. Malki, and M. Micoulaut, "Elastic flexibility, fast-ion conduction, boson and floppy modes in AgPO₃-AgI glasses examined in Raman scattering, IR reflectance,

MDSC, ac electrical conductivity and molar volume experiments”, Phys. Rev. Letters 98, 195501 (2007). (21 citations).

7. P. Boolchand, M. Jin, D. I. Novita, and S. Chakravarty,” Raman scattering as a probe of intermediate phases in glassy networks”, J. of Raman Scattering 38, 660 (2007). (20 citations).
8. C. Holbrook, P. Chen, D. Novita, and P. Boolchand,” Origin of Conductivity Threshold in the Solid Electrolyte Glass System: $(Ag_2S)_x(As_2S_3)_{1-x}$ “, J. of IEEE Transaction on Nanotechnology 6, 520 (2007). (4 citations).

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